Form PTO 1449		U.S. DEPARTMENT OF COMMERCE		ATTY DOCKET NO.		SERIAL NO.		
(Modified)		PATENT AND TRADEMARK OFFICE		217363US3		NEW APPLICATION		
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LIST OF REFERENCES CITED BY APPLICANT				Eisaku ITO, et al.				
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		NUMBER	DATE	COUNTRY		YES		
W	AO	5-222901	08/31/93	JAPAN (with English Abstract)			X	
W,	AP	11-247615	09/14/99	JAPAN (with English Abstract)			X	
W	AQ	10-196303	07/28/98	JAPAN (with English Abstract)			X	
W,	AR	2000-257447	09/19/00	JAPAN (with English Abstract)			X	
W	AS	2000-179303	06/27/00	JAPAN (with English Abstract)			X	
W	ΑT	2710729 .	10/24/97	JAPAN (Partial English Abstract)			X	
W	AU	10-274003	10/13/98	JAPAN (With English Abstract)			X	
W	AV	11-336506	12/07/99	JAPAN (With English Abstract)			X	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								
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SERIAL NO. ATTY DOCKET NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 (Modified) 217363US3 10/022,770 APPLICANT LIST OF REFERENCES CITED BY APPLICANT Eisaku ITO, et al. **GROUP FILING DATE** 3746 December 20, 2001 **U.S. PATENT DOCUMENTS** SUB **FILING DATE EXAMINER** DOCUMENT DATE NAME **CLASS** IF APPROPRIATE CLASS INITIAL NUMBER AA AB AC AD ΑE AF AG AΗ ΑI AJ ΑK ΑL AM ΑN **FOREIGN PATENT DOCUMENTS** TRANSLATION DOCUMENT DATE COUNTRY NUMBER YES NO Х **FRANCE** 584 884 02/17/25 ΑO CN Х 10/02/97 **GERMANY** W AP 196 12 394 Х AQ 58-20903 02/07/83 JAPAN (with English-Abetract) AR AS ΑT ΑU ΑV OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) AW MAY 2.1 2002

TECHNOLOGY CENTEH R37,0 AX AY **A7** Date Considered 1-24 84 Examiner VWOL *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.